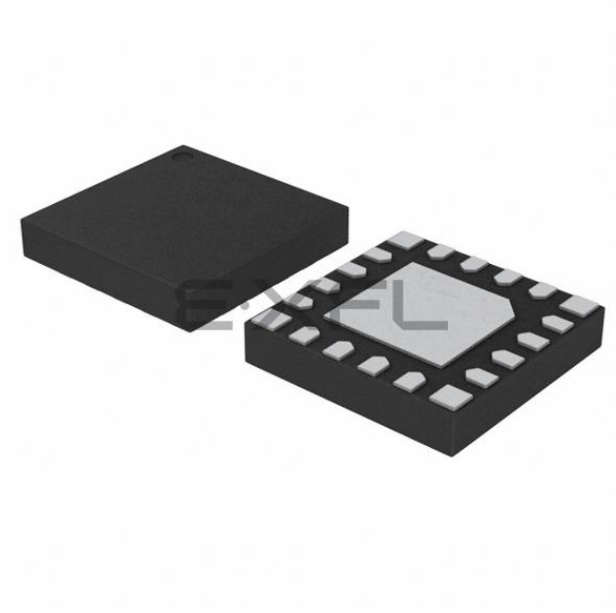

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	16
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 15x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	20-WFQFN Exposed Pad
Supplier Device Package	20-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb21f16i-c-qfn20

1. Feature List

The EFM8BB2 highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 50 MHz maximum operating frequency
- Memory:
  - Up to 16 KB flash memory, in-system re-programmable from firmware, including 1 KB of 64-byte sectors and 15 KB of 512-byte sectors.
  - Up to 2304 bytes RAM (including 256 bytes standard 8051 RAM and 2048 bytes on-chip XRAM)
- Power:
  - 5 V-input LDO regulator
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 22 total multifunction I/O pins:
  - All pins 5 V tolerant under bias
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 49 MHz oscillator with accuracy of ±1.5%
  - Internal 24.5 MHz oscillator with ±2% accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
- Timers/Counters and PWM:
  - 3-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 5 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- Communications and Digital Peripherals:
  - 2 x UART, up to 3 Mbaud
  - SPI™ Master / Slave, up to 12 Mbps
  - SMBus™/I2C™ Master / Slave, up to 400 kbps
  - I^2C High-Speed Slave, up to 3.4 Mbps
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
- Analog:
  - 12-Bit Analog-to-Digital Converter (ADC)
  - 2 x Low-current analog comparators with adjustable reference
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-loaded UART bootloader
- Temperature range -40 to 85 ºC or -40 to 125 ºC
  - Automotive grade available (requires PPAP)
- Single power supply of 2.2 to 3.6 V or 3.0 to 5.25 V
- QFN28, QSOP24, and QFN20 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8BB2 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 2.2 to 3.6 V operation (or up to 5.25 V with the 5 V regulator option) and is available in 28-pin QFN, 20-pin QFN, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

Timers (Timer 0, Timer 1, Timer 2, Timer 3, and Timer 4)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3 and Timer 4 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8.
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes.
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions.
- Baud rates up to SYSCLK/2 (transmit) or SYSCLK/8 (receive).
- 8- or 9-bit data.
- Automatic start and stop generation.
- Single-byte FIFO on transmit and receive.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 12 (CMP1) external positive inputs
- Up to 10 (CMP0) or 12 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset

3.9 Debugging

The EFM8BB2 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	1045	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	15	µA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, T_A = 25 °C	—	105	—	µA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 49 MHz, T_A = 25 °C	—	865	940	µA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	4	—	µA
ADC0 Always-on[4]	I_{ADC}	800 ksps, 10-bit conversions or 200 ksps, 12-bit conversions Normal bias settings V_{DD} = 3.0 V	—	820	1200	µA
		250 ksps, 10-bit conversions or 62.5 ksps 12-bit conversions Low power bias settings V_{DD} = 3.0 V	—	405	580	µA
ADC0 Burst Mode, 10-bit single conversions, external reference	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	370	—	µA
		100 ksps, V_{DD} = 3.0 V	—	185	—	µA
		10 ksps, V_{DD} = 3.0 V	—	20	—	µA
ADC0 Burst Mode, 10-bit single conversions, internal reference, Low power bias settings	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	485	—	µA
		100 ksps, V_{DD} = 3.0 V	—	245	—	µA
		10 ksps, V_{DD} = 3.0 V	—	25	—	µA
ADC0 Burst Mode, 12-bit single conversions, external reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V	—	505	—	µA
		50 ksps, V_{DD} = 3.0 V	—	255	—	µA
		10 ksps, V_{DD} = 3.0 V	—	50	—	µA
ADC0 Burst Mode, 12-bit single conversions, internal reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V, Normal bias	—	950	—	µA
		50 ksps, V_{DD} = 3.0 V, Low power bias	—	415	—	µA
		10 ksps, V_{DD} = 3.0 V, Low power bias	—	80	—	µA
Internal ADC0 Reference, Always-on[5]	I_{VREFFS}	Normal Power Mode	—	680	790	µA
		Low Power Mode	—	160	210	µA

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}		1.95	2.05	2.15	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on VDD	—	1.2	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t_{RMP}	Time to V_{DD} > 2.2 V	10	—	—	µs
Reset Delay from POR	t_{POR}	Relative to V_{DD} > V_{POR}	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	50	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	F_{SYSCLK} >1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1,2]	t_{WRITE}	One Byte, F_{SYSCLK} = 24.5 MHz	19	20	21	µs
Erase Time[1,2]	t_{ERASE}	One Page, F_{SYSCLK} = 24.5 MHz	5.2	5.35	5.5	ms
V_{DD} Voltage During Programming[3]	V_{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		20k	100k	—	Cycles

Note:

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUS-PENDWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	170	—	ns
Snooze Mode Wake-up Time	$t_{SLEEPWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	12	—	µs

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	PSS_{HFOSC0}	T_A = 25 °C	—	0.5	—	%/V
Temperature Sensitivity	TS_{HFOSC0}	V_{DD} = 3.0 V	—	40	—	ppm/°C
High Frequency Oscillator 1 (49 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	48.25	49	49.75	MHz
Power Supply Sensitivity	PSS_{HFOSC1}	T_A = 25 °C	—	0.02	—	%/V
Temperature Sensitivity	TS_{HFOSC1}	V_{DD} = 3.0 V	—	45	—	ppm/°C
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	PSS_{LFOSC}	T_A = 25 °C	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	V_{DD} = 3.0 V	—	65	—	ppm/°C

4.1.8 ADC

Table 4.8. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	12 Bit Mode	—	—	200	ksps
		10 Bit Mode	—	—	800	ksps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	62.5	ksps
		10 Bit Mode	—	—	250	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode, Reference is 2.4 V internal	—	—	6.25	MHz
		High Speed Mode, Reference is not 2.4 V internal	—	—	12.5	MHz
		Low Power Mode	—	—	4	MHz
Conversion Time	t_{CNV}	10-Bit Conversion, SAR Clock = 12.25 MHz, System Clock = 24.5 MHz.		1.1		µs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5	—	pF
		Gain = 0.5	—	2.5	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{DD}	V
Input Voltage Range[1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	$2xV_{REF}$	V
Power Supply Rejection Ratio	$PSRR_{ADC}$		—	70	—	dB
DC Performance						
Integral Nonlinearity	INL	12 Bit Mode	—	±1	±2.3	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode	-1	±0.7	1.9	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Offset Error	E_{OFF}	12 Bit Mode, VREF = 1.65 V	-3	0	3	LSB
		10 Bit Mode, VREF = 1.65 V	-2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Slope Error	E_M	12 Bit Mode	—	±0.02	±0.1	%
		10 Bit Mode	—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1 dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	71	—	dB
		10 Bit Mode	—	70	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	-79	—	dB
		10 Bit Mode	—	-70	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.

4.1.9 Voltage Reference

Table 4.9. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}	1.65 V Setting	1.62	1.65	1.68	V
		2.4 V Setting, V_{DD} > 2.6 V	2.35	2.4	2.45	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 800 ksps; VREF = 3.0 V	—	8	—	µA

4.1.10 Temperature Sensor

Table 4.10. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	T_A = 0 °C	—	757	—	mV
Offset Error[1]	E_{OFF}	T_A = 0 °C	—	17	—	mV
Slope	M		—	2.85	—	mV/°C
Slope Error[1]	E_M		—	70	—	µV/°
Linearity			—	0.5	—	°C
Turn-on Time			—	1.8	—	µs

Note:
1. Represents one standard deviation from the mean.

4.1.11 1.8 V Internal LDO Voltage Regulator

Table 4.11. 1.8V Internal LDO Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output Voltage	$V_{OUT\_1.8V}$		1.78	1.85	1.92	V

4.1.12 5 V Voltage Regulator

Table 4.12. 5V Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Voltage Range[1]	V_{REGIN}		3.0	—	5.25	V
Output Voltage on VDD[2]	V_{REGOUT}	Output Current = 1 to 100 mA Regulation range (VREGIN ≥ 4.1 V)	3.1	3.3	3.6	V
		Output Current = 1 to 100 mA Dropout range (VREGIN < 4.1 V)	—	V_{REGIN} – $V_{DROPOUT}$	—	V
Output Current[2]	I_{REGOUT}		—	—	100	mA
Dropout Voltage	$V_{DROPOUT}$	Output Current = 100 mA	—	—	0.8	V

Note:
1. Input range to meet the Output Voltage on VDD specification. If the 5V voltage regulator is not used, VREGIN should be tied to VDD.
2. Output current is total regulator output, including any current required by the device.

4.1.14 Port I/O

Table 4.14. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)[1]	V_{OH}	I_{OH} = -7 mA, V_{DD} ≥ 3.0 V	V_{DD} - 0.7	—	—	V
		I_{OH} = -3.3 mA, 2.2 V ≤ V_{DD} < 3.0 V	V_{DD} x 0.8	—	—	V
Output Low Voltage (High Drive)[1]	V_{OL}	I_{OL} = 13.5 mA, V_{DD} ≥ 3.0 V	—	—	0.6	V
		I_{OL} = 7 mA, 2.2 V ≤ V_{DD} < 3.0 V	—	—	V_{DD} x 0.2	V
Output High Voltage (Low Drive)[1]	V_{OH}	I_{OH} = -4.75 mA, V_{DD} ≥ 3.0 V	V_{DD} - 0.7	—	—	V
		I_{OH} = -2.25 mA, 2.2 V ≤ V_{DD} < 3.0 V	V_{DD} x 0.8	—	—	V
Output Low Voltage (Low Drive)[1]	V_{OL}	I_{OL} = 6.5 mA, V_{DD} ≥ 3.0 V	—	—	0.6	V
		I_{OL} = 3.5 mA, 2.2 V ≤ V_{DD} < 3.0 V	—	—	V_{DD} x 0.2	V
Input High Voltage	V_{IH}		V_{DD} - 0.6	—	—	V
Input Low Voltage	V_{IL}		—	—	0.6	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current (V_{IN} = 0 V)	I_{PU}	V_{DD} = 3.6	-30	-20	-10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	GND < V_{IN} < V_{DD}	-1.1	—	1.1	µA
Input Leakage Current with V_{IN} above V_{DD}	I_{LK}	V_{DD} < V_{IN} < V_{DD}+2.0 V	0	5	150	µA

Note:
1. See Figure 4.6 Typical V_{OH} Curves on page 28 and Figure 4.7 Typical V_{OL} Curves on page 28 for more information.

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance (Junction to Ambient)	θ_{JA}	QFN-20 Packages	—	60	—	°C/W
		QFN-28 Packages	—	26	—	°C/W
		QSOP-24 Packages	—	65	—	°C/W
Thermal Resistance (Junction to Case)	θ_{JC}	QFN-20 Packages	—	28.86	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

Table 6.1. Pin Definitions for EFM8BB2x-QFN28

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF
3	GND	Ground			
4	N/C	No Connection			
5	N/C	No Connection			
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	P3.1	Multifunction I/O			
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
11	P2.3	Multifunction I/O	Yes	P2MAT.3	ADC0.23 CP1P.12 CP1N.12
12	P2.2	Multifunction I/O	Yes	P2MAT.2	ADC0.22 CP1P.11 CP1N.11
13	P2.1	Multifunction I/O	Yes	P2MAT.1	ADC0.21 CP1P.10 CP1N.10
14	P2.0	Multifunction I/O	Yes	P2MAT.0	ADC0.20 CP1P.9 CP1N.9
15	P1.7	Multifunction I/O	Yes	P1MAT.7	ADC0.15 CP1P.7 CP1N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
16	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
17	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CMP1P.3 CMP1N.3
18	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CMP1P.2 CMP1N.2
19	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1 CMP0P.10 CMP0N.10
20	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0 CMP0P.9 CMP0N.9
21	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7
22	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.6 CMP0N.6
23	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX	ADC0.5 CMP0P.5 CMP0N.5
24	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX	ADC0.4 CMP0P.4 CMP0N.4

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P2.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		
7	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14 CMP1P.6 CMP1N.6
8	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP1P.5 CMP1N.5
9	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
10	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SCL	ADC0.11 CMP1P.3 CMP1N.3
11	P1.2	Multifunction I/O	Yes	P1MAT.2 I2C0_SDA	ADC0.10 CMP1P.2 CMP1N.2
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1 CMP0P.10 CMP0N.10
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0 CMP0P.9 CMP0N.9
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7

7. QFN28 Package Specifications

7.1 QFN28 Package Dimensions

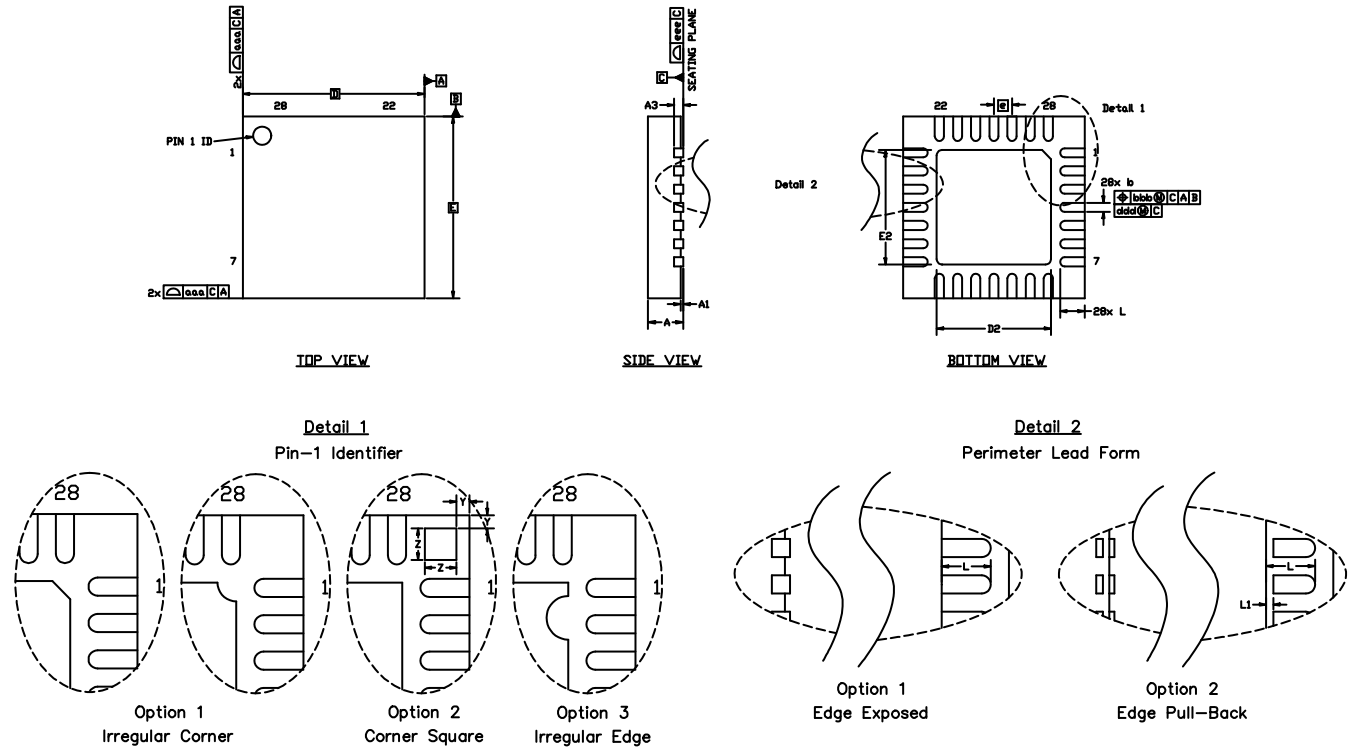

Figure 7.1. QFN28 Package Drawing

Table 7.1. QFN28 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	—	0.05
A3		0.20 REF	
b	0.20	0.25	0.30
D		5.00 BSC	
D2	3.15	3.25	3.35
e		0.50 BSC	
E		5.00 BSC	
E2	3.15	3.25	3.35
L	0.45	0.55	0.65
aaa		0.10	
bbb		0.10	
ddd		0.05	

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9. QFN20 Package Specifications

9.1 QFN20 Package Dimensions

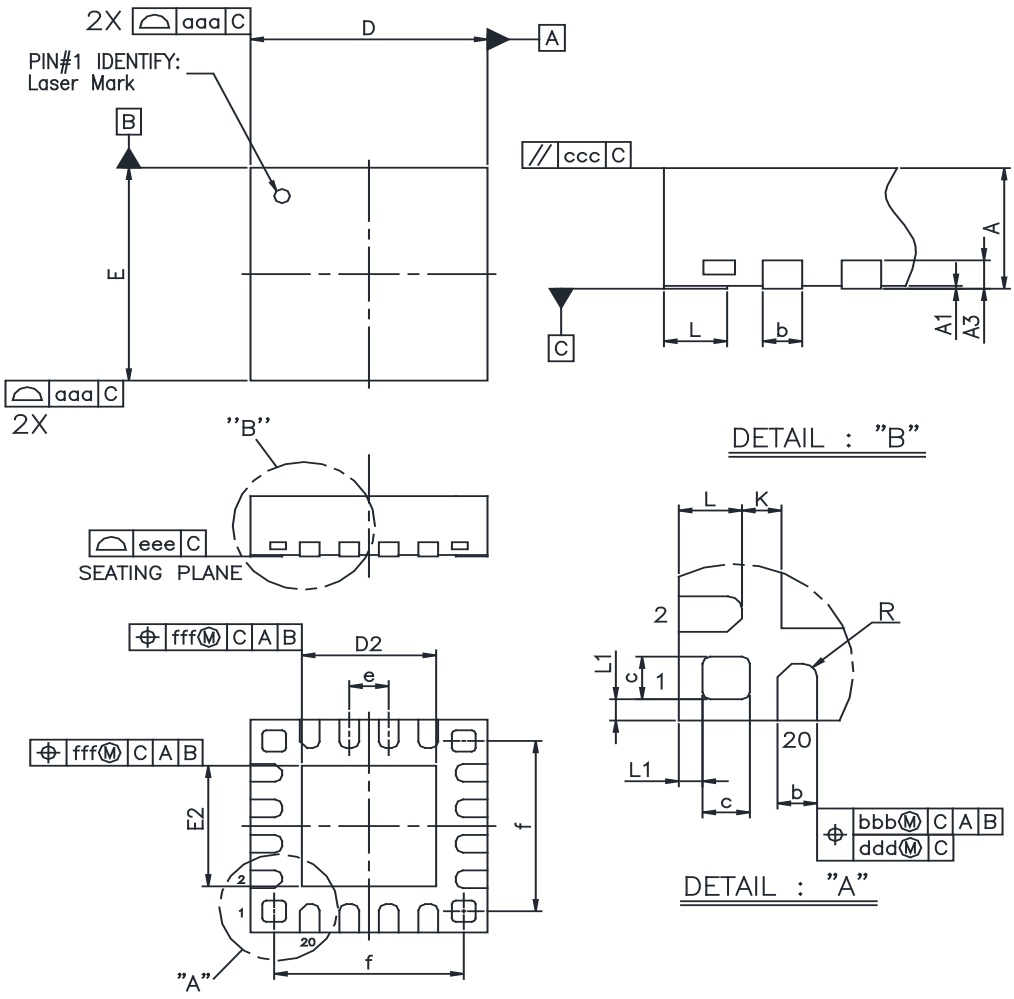

Figure 9.1. QFN20 Package Drawing

Table 9.1. QFN20 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3		0.20 REF	
b	0.18	0.25	0.30
c	0.25	0.30	0.35
D		3.00 BSC	
D2	1.6	1.70	1.80
e		0.50 BSC	

9.2 QFN20 PCB Land Pattern

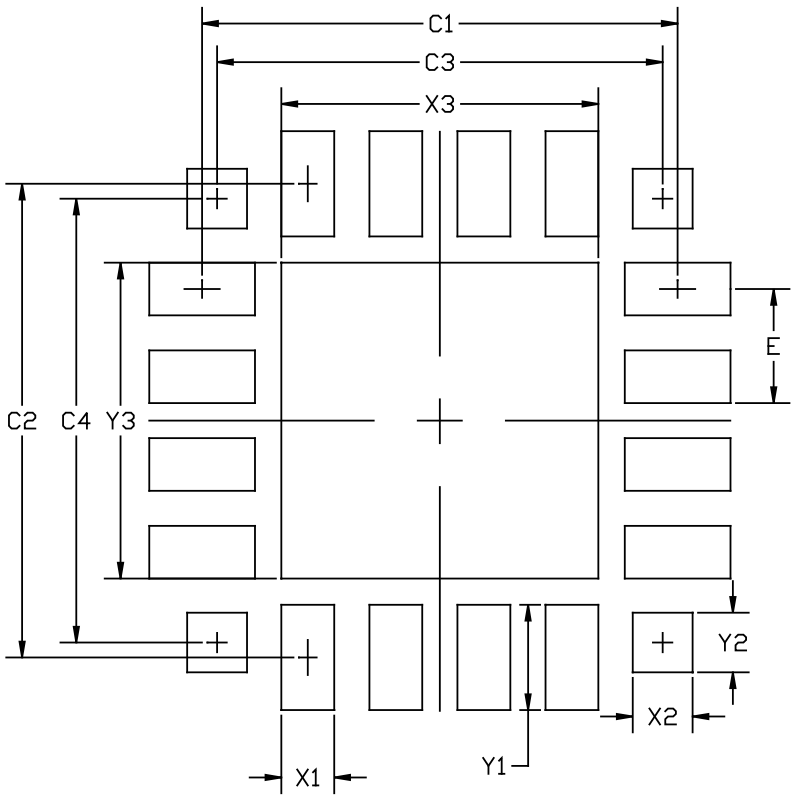

Figure 9.2. QFN20 PCB Land Pattern Drawing

Table 9.2. QFN20 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.10	
C2	3.10	
C3	2.50	
C4	2.50	
E	0.50	
X1	0.30	
X2	0.25	0.35
X3	1.80	
Y1	0.90	
Y2	0.25	0.35
Y3	1.80	

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
6. The stencil thickness should be 0.125 mm (5 mils).
7. The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
8. A 2 x 2 array of 0.75 mm openings on a 0.95 mm pitch should be used for the center pad to assure proper paste volume.
9. A No-Clean, Type-3 solder paste is recommended.
10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.3 QFN20 Package Marking

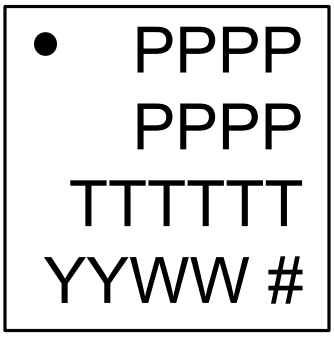

Figure 9.3. QFN20 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

10. Revision History

10.1 Revision 1.31

November 7, 2016

Updated typical and maximum specifications in 4.1.2 Power Consumption.

Added 4.1.11 1.8 V Internal LDO Voltage Regulator.

10.2 Revision 1.3

August 11, 2016

Added A-grade parts.

Added Thermal Resistance (Junction to Case) for QFN20 packages to 4.2 Thermal Conditions.

Added a note to Table 4.2 Power Consumption on page 13 providing more information about the Comparator Reference specification.

Added a note linking to the Typical VOH and VOL Performance graphs in 4.1.14 Port I/O.

Specified the sizes of the SMBus and I2CSLAVE transmit and receive FIFOs.

Added a note to 3.1 Introduction referencing the Reference Manual.

10.3 Revision 1.2

February 10, 2016

Updated Figure 5.3 Debug Connection Diagram on page 30 to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in 3.10 Bootloader.

Added I-grade parts.

Adjusted and added maximum specifications in 4.1.2 Power Consumption for G-grade devices and added a note on which high frequency oscillator is used for the specification.

Adjusted the Total Current Sunk into Supply Pin and Total Current Sourced out of Ground Pin specifications in 4.3 Absolute Maximum Ratings.

10.4 Revision 1.1

December 16, 2015

Updated 3.2 Power to properly reflect that a comparator falling edge wakes the device from Suspend and Snooze.

Added Note 2 to Table 4.1 Recommended Operating Conditions on page 12.

Added 5.2 Debug.

10.5 Revision 1.0

Updated any TBD numbers in and adjusted various specifications.

Updated VOH and VOL graphs in Figure 4.6 Typical V_{OH} Curves on page 28 and Figure 4.7 Typical V_{OL} Curves on page 28 and updated the VOH and VOL specifications in Table 4.14 Port I/O on page 23.

Added more information to 3.10 Bootloader.

Updated part numbers to Revision C.

Table of Contents